Sheet <u>1</u> of <u>2</u>

Substitute Form PTO-1449 U.S. Department of Commerce (Modified) Patent and Trademark Office		Attorney's Docket No. 06975-447001	Application No. 10/651,303	
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CER \$1.98(b))		Applicant Mehanna et al.		
		Filing Date August 29, 2003	Group Art Unit 2171	

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Examiner Signature			Date Considered
/Jeffrey Swearingen/			02/18/2008

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